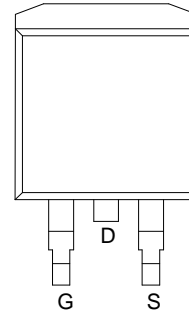


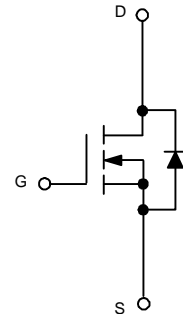
Features

- 30V/12A,
 $R_{DS(ON)}=75m\Omega$ (typ.) @ $V_{GS}=10V$
 $R_{DS(ON)}=100m\Omega$ (typ.) @ $V_{GS}=4.5V$
- Super High Dense Cell Design
- Reliable and Rugged
- Lead Free Available (RoHS Compliant)

Pin Description



Top View of TO-263

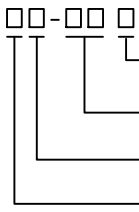



N-Channel MOSFET

Applications

- Power Management in Desktop Computer or DC/DC Converters

Ordering and Marking Information

<p>APM3055N</p>  <p>Lead Free Code</p> <p>Handling Code</p> <p>Temp. Range</p> <p>Package Code</p>	<p>Package Code G : TO-263</p> <p>Operating Junction Temp. Range C : -55 to 150°C</p> <p>Handling Code TU : Tube TR : Tape & Reel</p> <p>Lead Free Code L : Lead Free Device</p>
<p>APM3055N G:</p> 	<p>XXXXX - Date Code</p>

Note: ANPEC lead-free products contain molding compounds and 100% matte tin plate termination finish; which are fully compliant with RoHS and compatible with both SnPb and lead-free soldering operations. ANPEC lead-free products meet or exceed the lead-free requirements of IPC/JEDEC J STD-020C for MSL classification at lead-free peak reflow temperature.

ANPEC reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.

Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Ratings ($T_A=25^\circ\text{C}$ Unless Otherwise Noted)				
V_{DSS}	Drain-Source Voltage	30	V	
V_{GSS}	Gate-Source Voltage	± 20		
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$	
T_{STG}	Storage Temperature Range	-55 to 150		
I_S	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$ 8	A	
Mounted on Large Heat Sink				
I_{DP}	300 μs Pulse Drain Current Tested	$T_C=25^\circ\text{C}$	48	A
		$T_C=100^\circ\text{C}$	48	
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	12*	
		$T_C=100^\circ\text{C}$	12	
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	62.5	W
		$T_C=100^\circ\text{C}$	25	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	2	$^\circ\text{C/W}$	
Mounted on PCB of 1in² pad area				
I_{DP}	300 μs Pulse Drain Current Tested	$T_A=25^\circ\text{C}$	16	A
		$T_A=100^\circ\text{C}$	10	
I_D	Continuous Drain Current	$T_A=25^\circ\text{C}$	4.3	
		$T_A=100^\circ\text{C}$	3.1	
P_D	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	2.8	W
		$T_A=100^\circ\text{C}$	1.1	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	45	$^\circ\text{C/W}$	
Mounted on PCB of Minimum Footprint				
I_{DP}	300 μs Pulse Drain Current Tested	$T_A=25^\circ\text{C}$	14	A
		$T_A=100^\circ\text{C}$	8	
I_D	Continuous Drain Current	$T_A=25^\circ\text{C}$	3.5	
		$T_A=100^\circ\text{C}$	2	
P_D	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	2	W
		$T_A=100^\circ\text{C}$	0.8	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	62.5	$^\circ\text{C/W}$	

Notes:

* Current limited by bond wire.

Electrical Characteristics (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	APM3055NG			Unit
			Min.	Typ.	Max.	
Static						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =24V, V _{GS} =0V T _J =85°C			1 30	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	1	1.5	2	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V			±100	nA
R _{DS(ON)} ^a	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =12A		75	100	mΩ
		V _{GS} =4.5V, I _{DS} =6A		100	200	
Diode						
V _{SD} ^a	Diode Forward Voltage	I _{SD} =3A, V _{GS} =0V		0.8	1.3	V
t _{rr}	Reverse Recovery Time	I _{DS} =12A, dI _{SD} /dt=100A/μs		20		ns
Q _{rr}	Reverse Recovery Charge			11		nC
Dynamic^b						
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz		2.2		Ω
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, Frequency=1.0MHz		390		pF
C _{oss}	Output Capacitance			65		
C _{rss}	Reverse Transfer Capacitance			35		
t _{d(ON)}	Turn-on Delay Time	V _{DD} =15V, R _L =15Ω, I _{DS} =1A, V _{GEN} =10V, R _G =6Ω		3	6	ns
T _r	Turn-on Rise Time			10	19	
t _{d(OFF)}	Turn-off Delay Time			15	28	
T _f	Turn-off Fall Time			2	5	
Gate Charge^b						
Q _g	Total Gate Charge	V _{DS} =15V, V _{GS} =10V, I _{DS} =12A		7.7	11	nC
Q _{gs}	Gate-Source Charge			1.7		
Q _{gd}	Gate-Drain Charge			1.1		

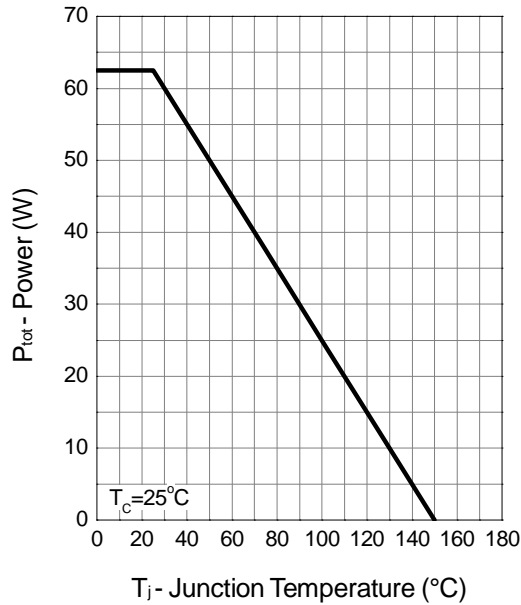
Notes:

a : Pulse test ; pulse width≤300μs, duty cycle≤2%.

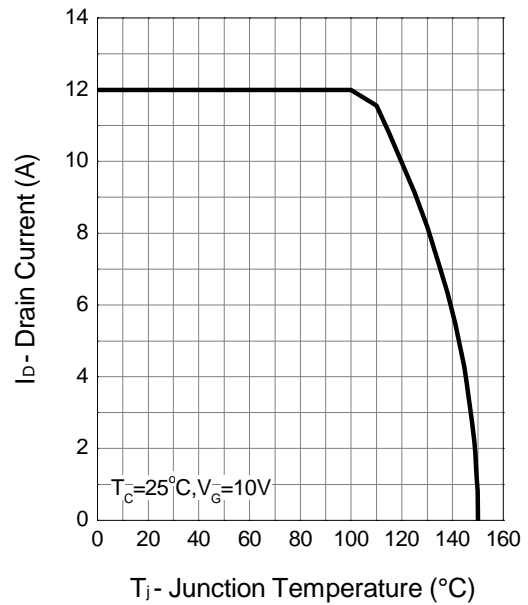
b : Guaranteed by design, not subject to production testing.

Typical Characteristics

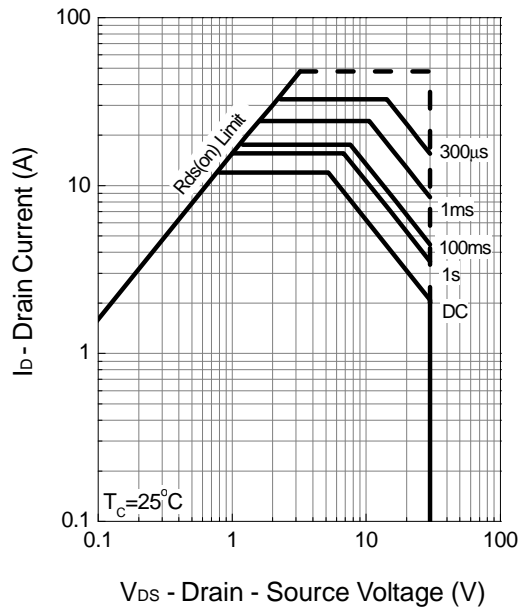
Power Dissipation



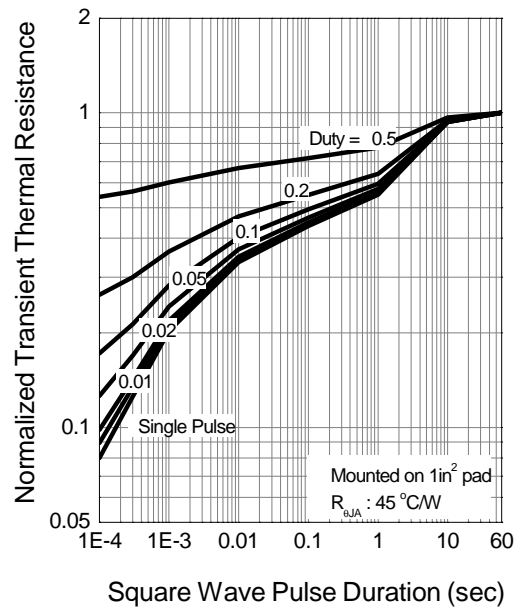
Drain Current



Safe Operation Area

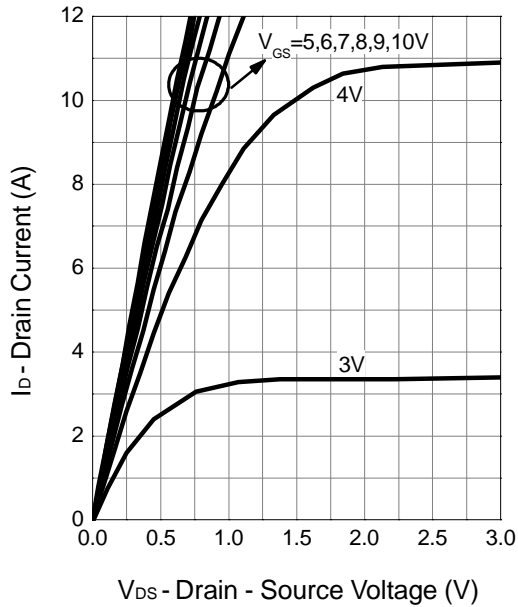


Thermal Transient Impedance

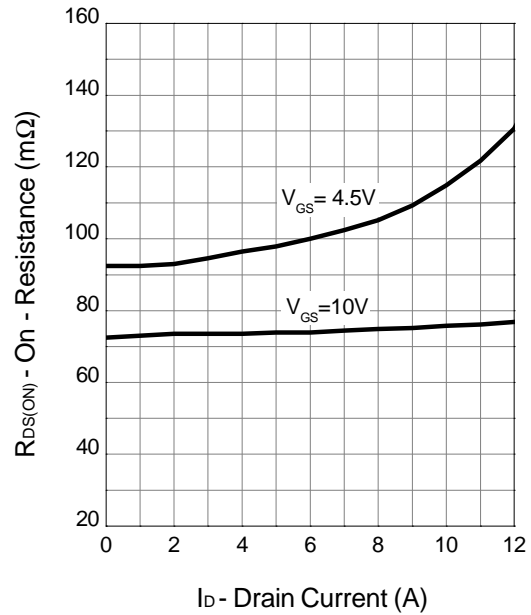


Typical Characteristics (Cont.)

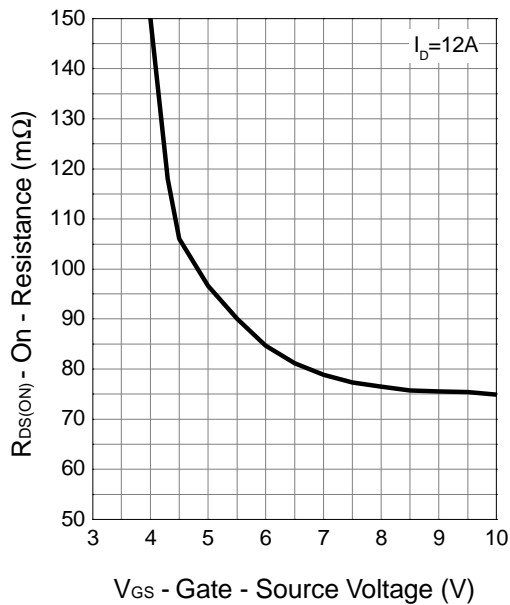
Output Characteristics



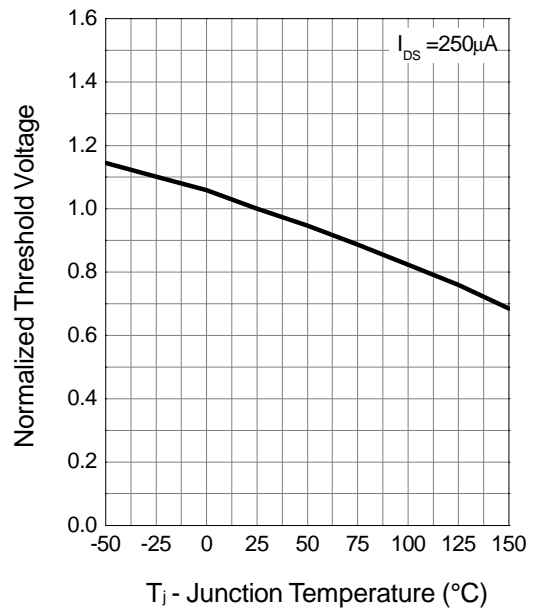
Drain-Source On Resistance



Drain-Source On Resistance

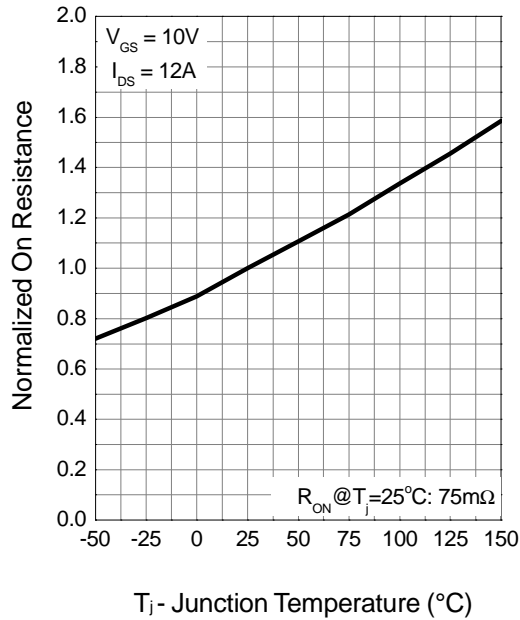


Gate Threshold Voltage

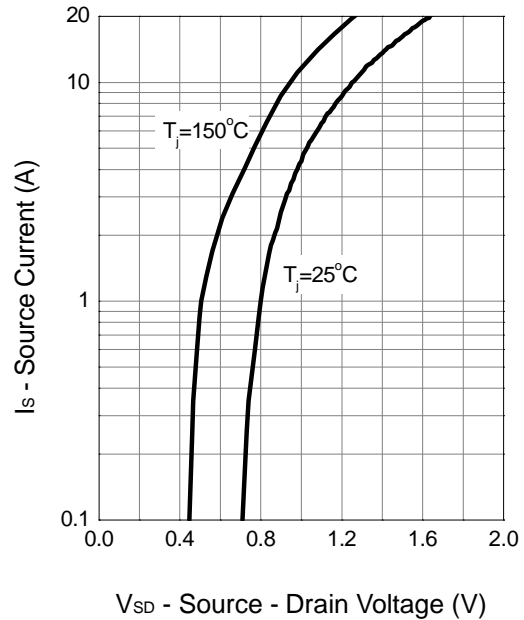


Typical Characteristics (Cont.)

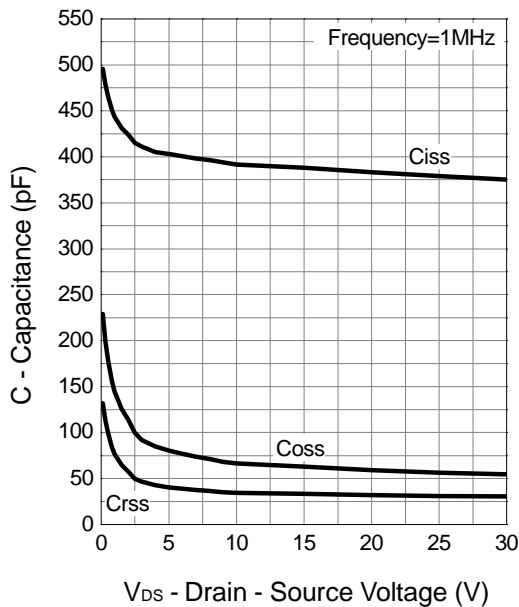
Drain-Source On Resistance



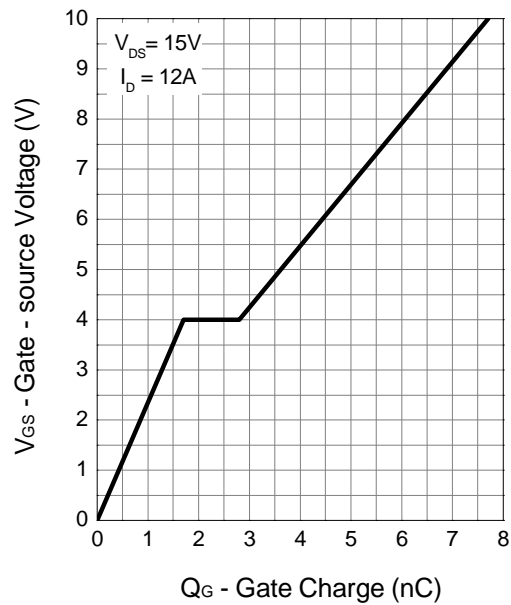
Source-Drain Diode Forward



Capacitance

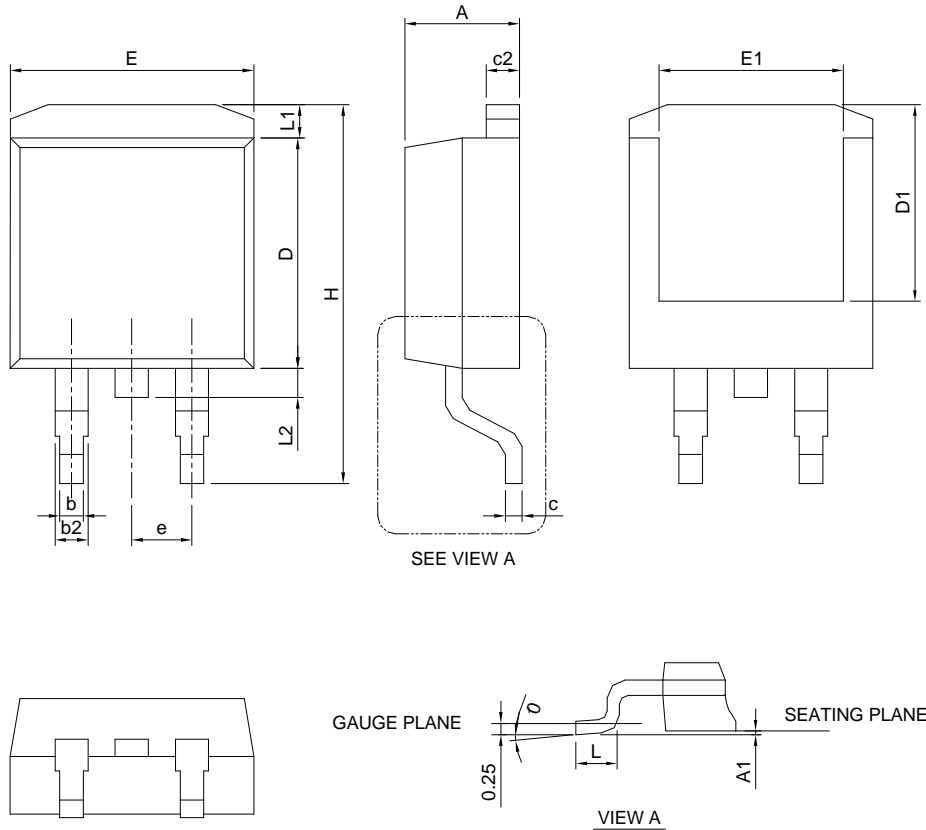


Gate Charge



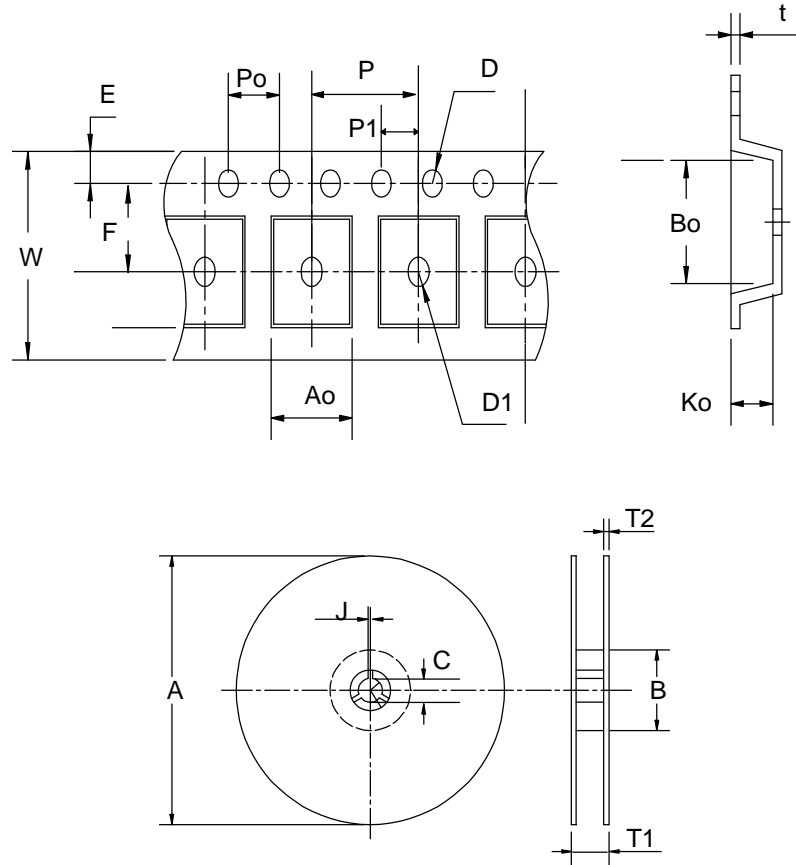
Packaging Information

TO-263 (Reference JEDEC Registration TO-263)



Dim	Millimeters		Inches	
	Min.	Max.	Min.	Max.
A	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b2	1.14	1.78	0.045	0.070
c	0.38	0.74	0.015	0.029
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
E	9.65	11.43	0.380	0.450
E1	6.22	-	0.245	-
e	2.54 BSC		0.100 BSC	
L	1.78	2.79	0.070	0.110
L1	-	1.68	-	0.066
L2	-	1.78	-	0.070
	0°	8°	0°	8°

Carrier Tape & Reel Dimensions



Application	A	B	C	J	T1	T2	W	P	E
TO-263	380±3	80 ± 2	13 ± 0.5	2 ± 0.5	24 ± 4	2± 0.3	24 +0.3 -0.1	16 ± 0.1	1.75± 0.1
	F	D	D1	Po	P1	Ao	Bo	Ko	t
	11.5 ± 0.1	1.5 +0.1	1.5± 0.25	4.0 ± 0.1	2.0 ± 0.1	10.8 ± 0.1	16.1± 0.1	5.2± 0.1	0.35±0.013

(mm)

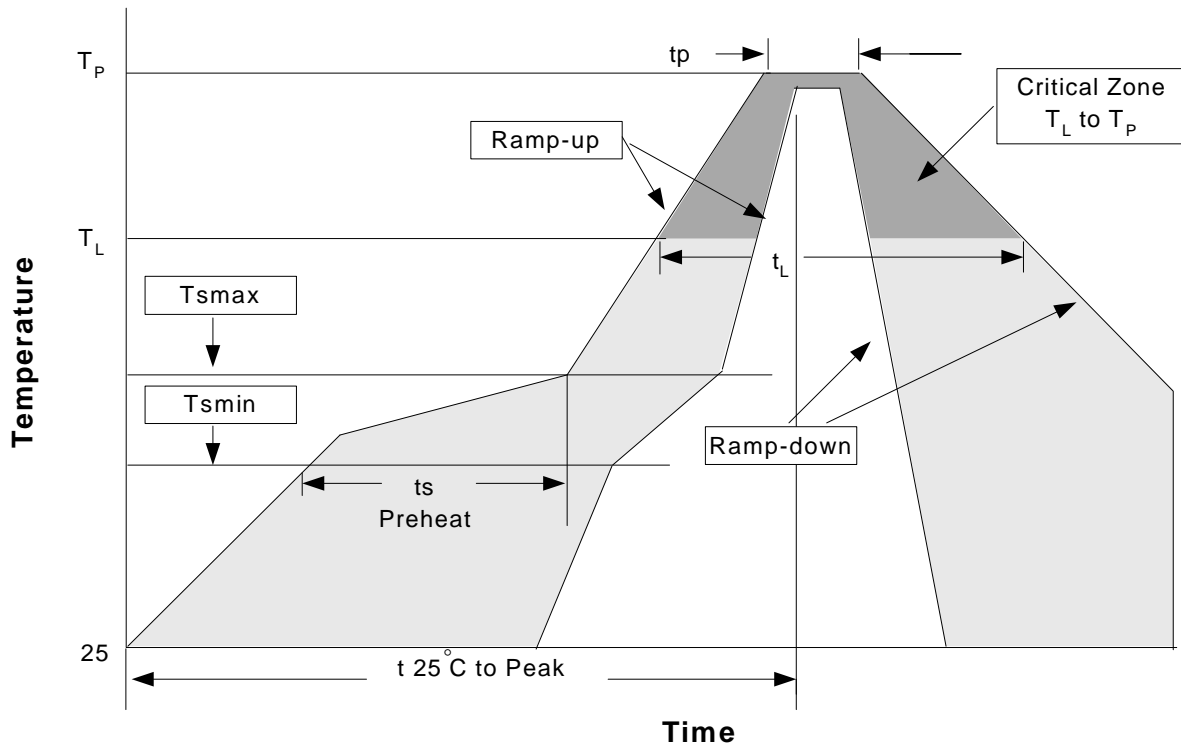
Cover Tape Dimensions

Application	Carrier Width	Cover Tape Width	Devices Per Reel
TO- 263	24	21.3	800

Physical Specifications

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb), 100%Sn
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.

Reflow Condition (IR/Convection or VPR Reflow)



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate (T_L to T_P)	3°C/second max.	3°C/second max.
Preheat		
- Temperature Min (T_{smin})	100°C	150°C
- Temperature Max (T_{smax})	150°C	200°C
- Time (min to max) (t_s)	60-120 seconds	60-180 seconds
Time maintained above:		
- Temperature (T_L)	183°C	217°C
- Time (t_L)	60-150 seconds	60-150 seconds
Peak/Classification Temperature (T_p)	See table 1	See table 2
Time within 5°C of actual Peak Temperature (t_p)	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.	6°C/second max.
Time 25°C to Peak Temperature	6 minutes max.	8 minutes max.

Notes: All temperatures refer to topside of the package .Measured on the body surface.

Classification Reflow Profiles(Cont.)

Table 1. SnPb Eutectic Process – Package Peak Reflow Temperatures

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	240 +0/-5°C	225 +0/-5°C
≥2.5 mm	225 +0/-5°C	225 +0/-5°C

Table 2. Pb-free Process – Package Classification Reflow Temperatures

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 +0°C*	260 +0°C*	260 +0°C*
1.6 mm – 2.5 mm	260 +0°C*	250 +0°C*	245 +0°C*
≥2.5 mm	250 +0°C*	245 +0°C*	245 +0°C*

*Tolerance: The device manufacturer/supplier **shall** assure process compatibility up to and including the stated classification temperature (this means Peak reflow temperature +0°C. For example 260°C+0°C) at the rated MSL level.

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C,5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
TST	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

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